



XA-9999
PATENT APPLICATION

IN THE UNITED STATES PATENT AND TRADEMARK OFFICE

In re the application of:

Tomohiro MIYASHITA

Appln. No.: 10/721,994

Filed: November 26, 2003

For: MICROSCOPE OPTICAL SYSTEM AND MICROSCOPE OBJECTIVE
LENS

* * *

SUPPLEMENTAL
INFORMATION DISCLOSURE STATEMENT

Commissioner for Patents
P.O. Box 1450
Alexandria, VA 22313-1450

Sir:

Supplementing the Information Disclosure Statement dated November 26, 2003, and without any assertion as to materiality or prior art effect, the documents listed on the attached Form PTO-1449 are hereby cited.

English abstracts of the listed documents were submitted with the Information Disclosure Statement dated November 26, 2003. Enclosed herewith are copies the Japanese Laid-Open Patent Applications cited.

The Commissioner is hereby authorized to charge to Deposit Account No. 50-1165 any fees under 37 C.F.R. §§ 1.16 and 1.17 that may be required by this paper and to credit any overpayment to that Account. If any extension of time is required in connection with the filing of this paper and has not been requested separately, such extension is hereby requested.

Respectfully submitted,

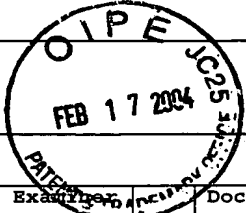
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February 17, 2004

FORM PTO-1449				Atty. Docket No. XA-9999		Appln. No. 10/721,994	
<u>LIST OF DOCUMENTS CITED BY APPLICANT</u>				Applicant Tomohiro MIYASHITA			
				November 26, 2003		Group	
				U.S. PATENT DOCUMENTS			
Examiner Initial	Document Number	Date	Name	Class	Sub- class	Filing Date	
AA							
AB							
AC							
AD							
AE							
AF							
AG							
AH							
AI							
FOREIGN PATENT DOCUMENTS							
Examiner Initial	Document Number	Date	Country	Class	Sub- class	Translation	
AJ	✓ 2000-171721	06/23/00	Japan			Abstract	
AK	✓ 2001-166215	06/22/01	Japan			Abstract	
AL	✓ 09-033818	02/07/97	Japan			Abstract	
AM							
AN							
AO							
OTHER (including author, title, date, pertinent pages, etc.)							
AP							
AQ							
AR							
Examiner				Date Considered			
EXAMINER: Initial if reference considered, whether or not citation is in conformance with MPEP 609; draw line through citation if not in conformance and not considered. Include copy of this form with next communication to Applicant.							